

QDA

27/02/2023

①

- ① Quality of design vs. Quality of conformance
- ② Measurement systems (Veracity in the 4 V's)
- ③ Quality data modelling

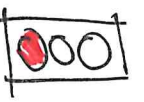


Quality of design



$D \in [LSL, USL]$  → pin is conforming to requirements

⇒ it is NOT defective

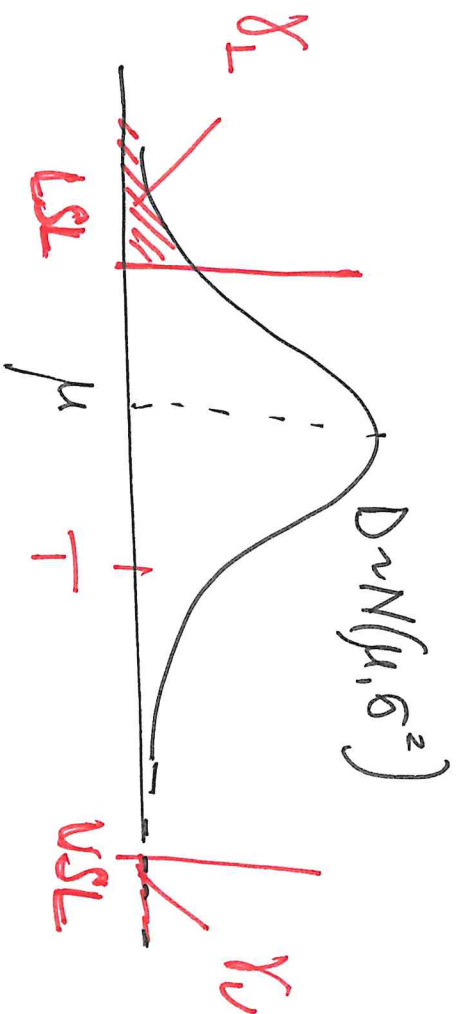


$D \notin [LSL, USL]$

→ pin is NOT conforming  
⇒ it is defective



3

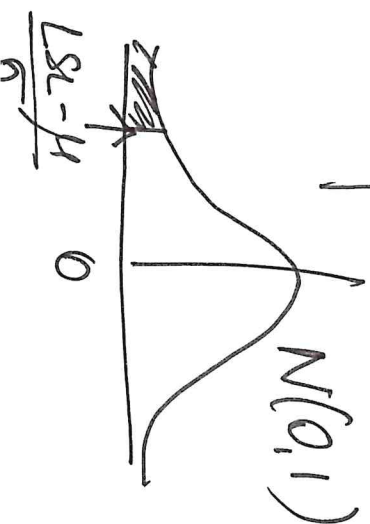


$LSL, USL = \text{design}$   
 $D \sim N(\mu, \sigma^2) = \text{process production}$

$Y_L = \text{probability of a defective item because of violation of the } LSL$

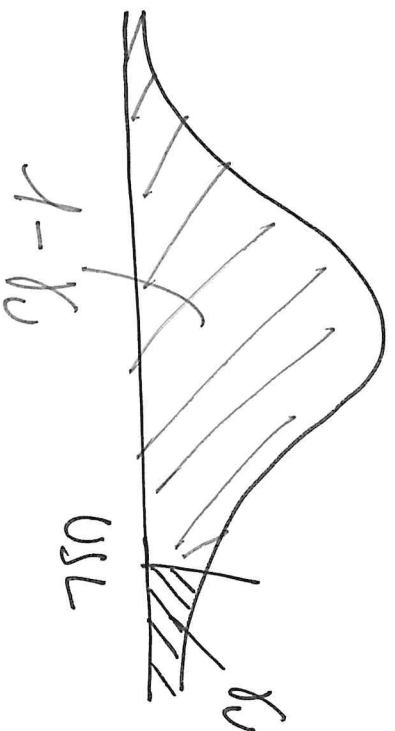
$Y_U = \text{probability of the } USL$

$$Y_L = P(D \leq LSL \mid D \sim N(\mu, \sigma^2)) = \Phi\left(\frac{LSL - \mu}{\sigma}\right) = P\left(Z \leq \frac{LSL - \mu}{\sigma}\right)$$



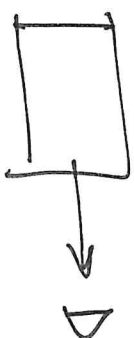
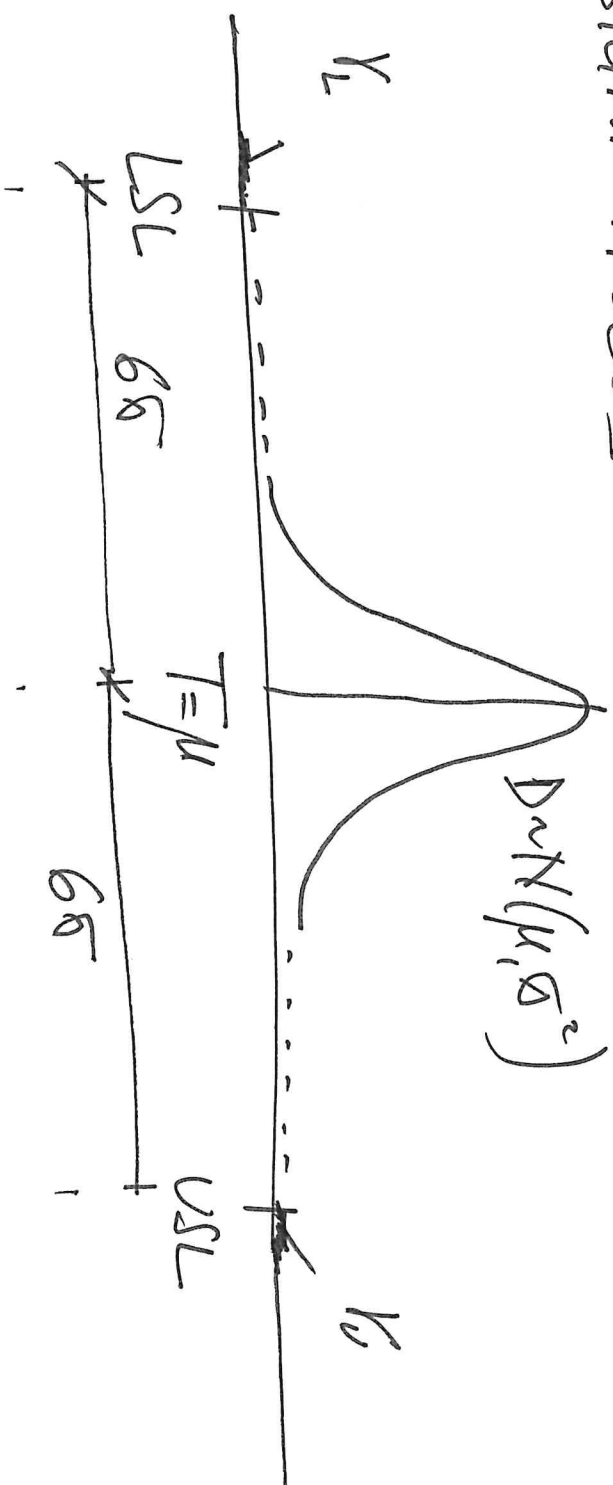
$$Y_0 = P(D \geq USL \mid \underbrace{D \sim N(\mu, \sigma^2)}_{(*)}) = 1 - P(D \leq \underline{USL} \mid \underbrace{(*)}_*) = 1 - \Phi\left(\frac{USL - \mu}{\sigma}\right) \quad (4)$$

NOTE :  $P(D \geq USL) = P(D > USL)$  if  $D$  continuous random variable  
 $P(D \leq LSL) = P(D < LSL)$

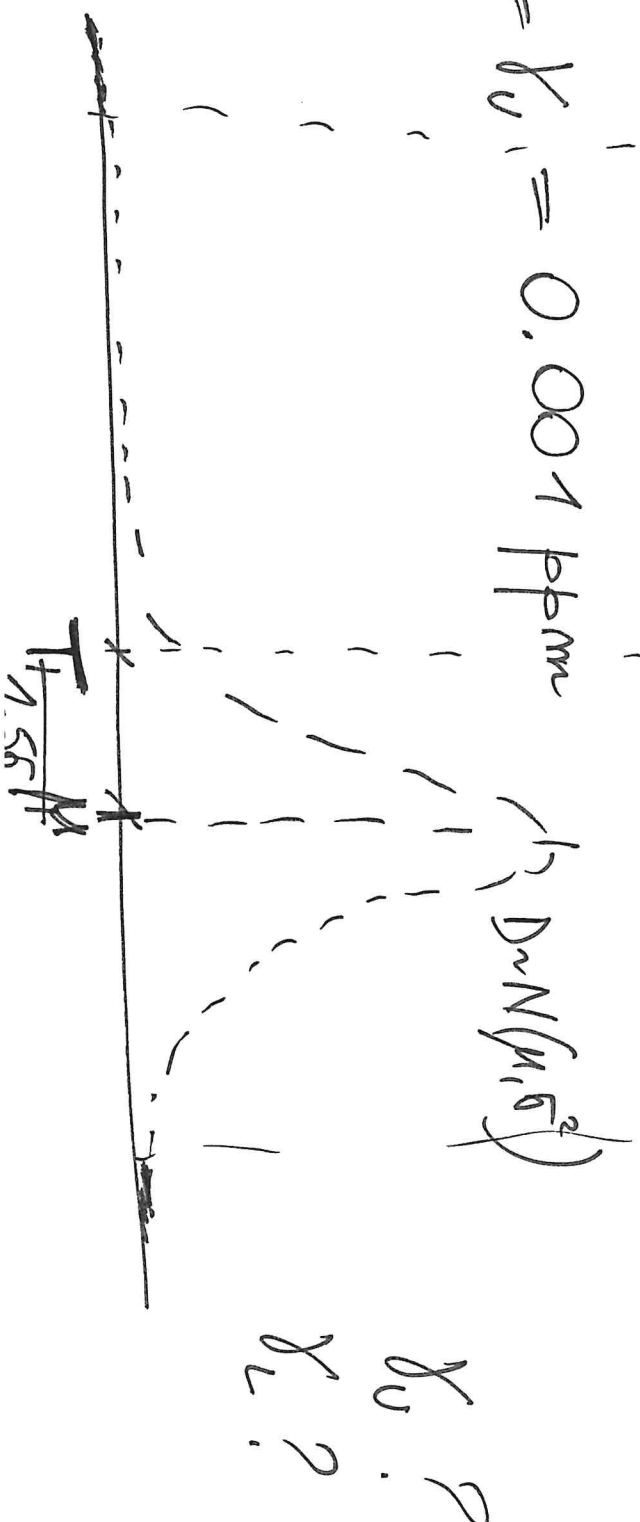


# 6 SIGMA PROCESS

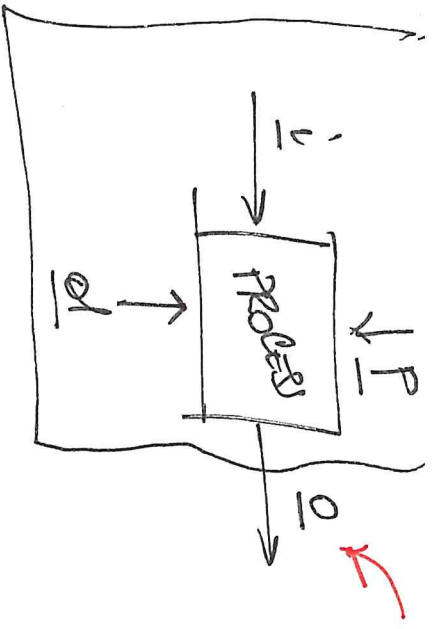
(5)



$$Y_L = Y_U = 0.001 \text{ ppm}$$

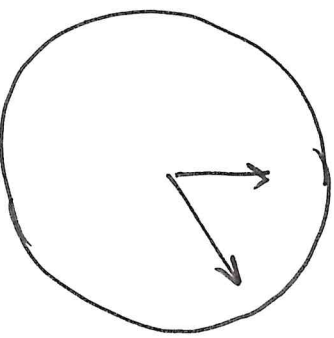


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PAST  
—  
O MODEL —  
FUTURE  
—  
ACTIONS

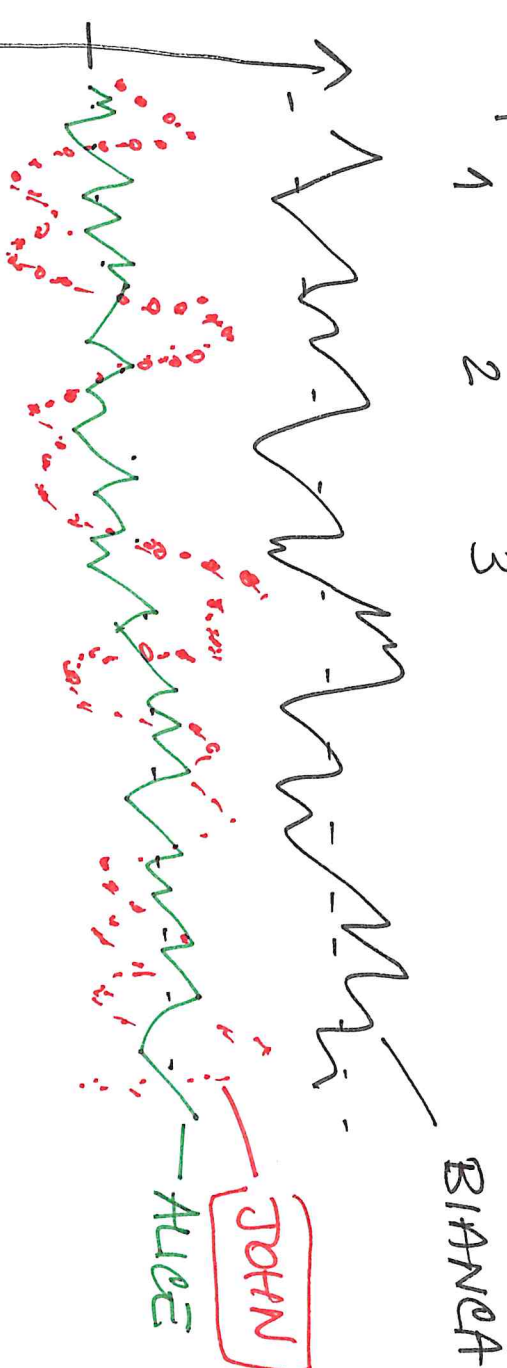
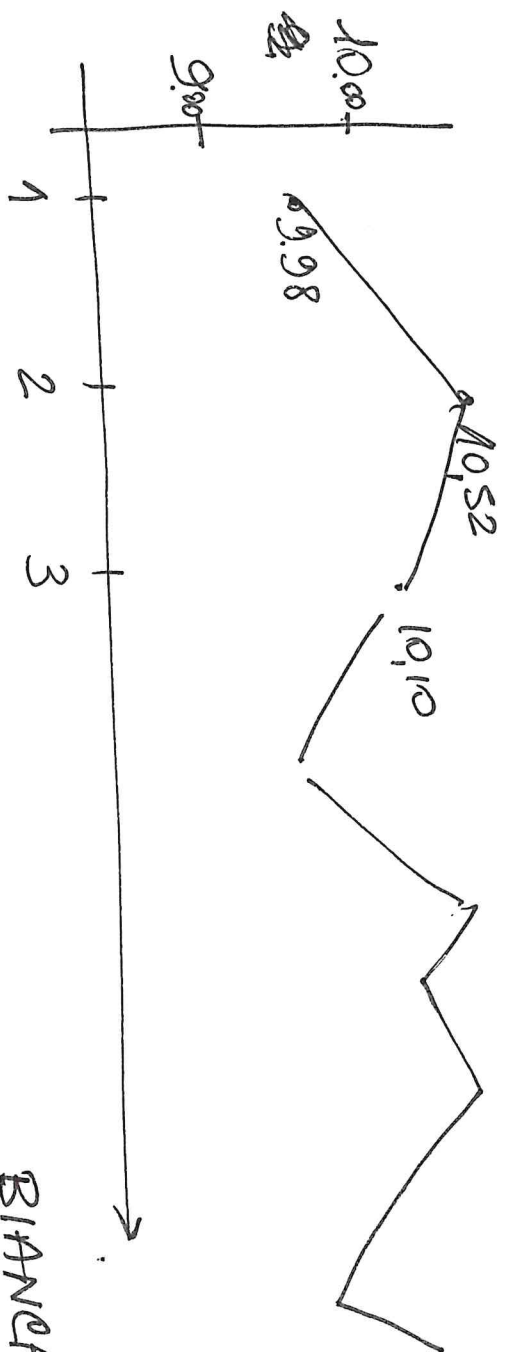
Veracity of my data  $\rightarrow$  CHECK MEASUREMENT  
SYSTEM (of THE OUTPUT)



STOPWATCH (Alarm)  
Assume you want to "measure"  
10 seconds on your watch

9,98    10,52    10,10    .....  
9,98

(7)



$T=10$

JOHN:

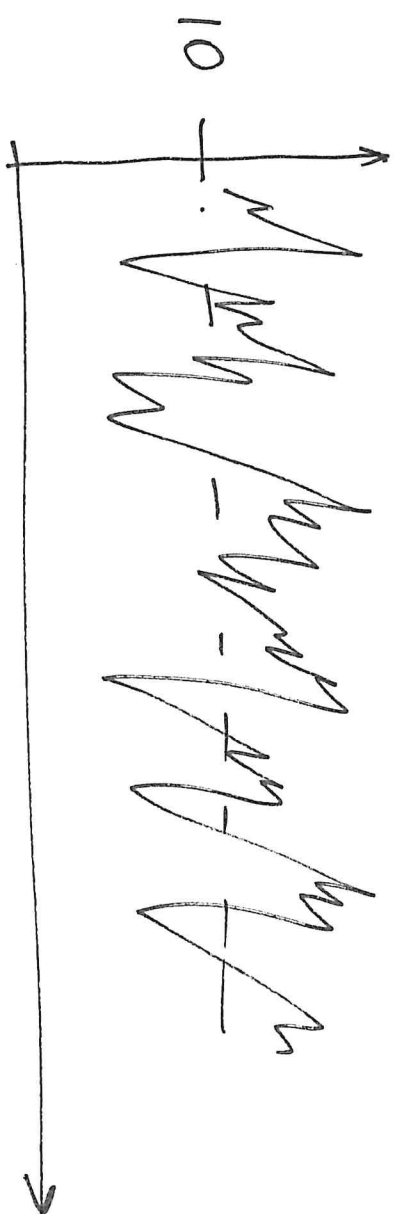
$$\bar{Y} = \frac{\sum_{i=1}^n Y_i}{n}$$

$$Y \sim N(\mu, \sigma^2) \quad (Y_i \text{ indep}) \quad V(\bar{Y}) = \frac{\sigma^2}{n}$$

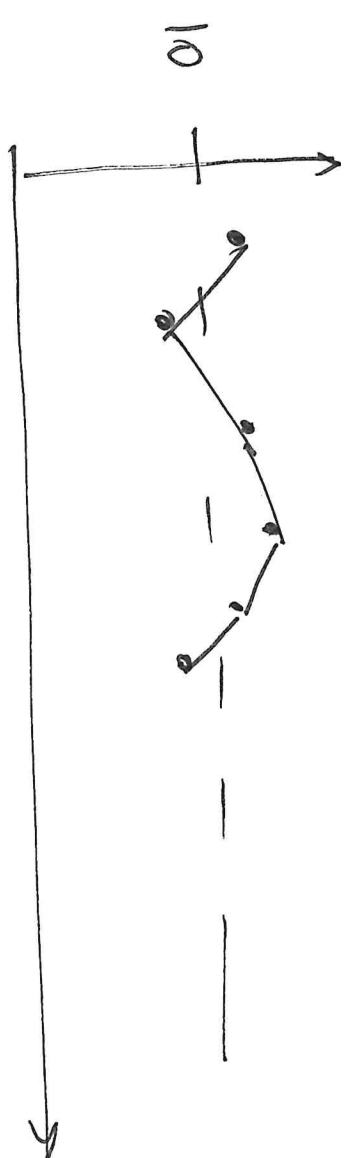
$$V(\bar{Y}) = \frac{\sigma^2}{n} = \frac{1}{n^2} \sum V(Y_i) = \frac{n\sigma^2}{n^2}$$



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John's  $y_i$ 's



John's  $\bar{y}_i$

$$V(Y_i) = \sigma^2 \quad V(\bar{Y}) = \frac{\sigma^2}{n}$$